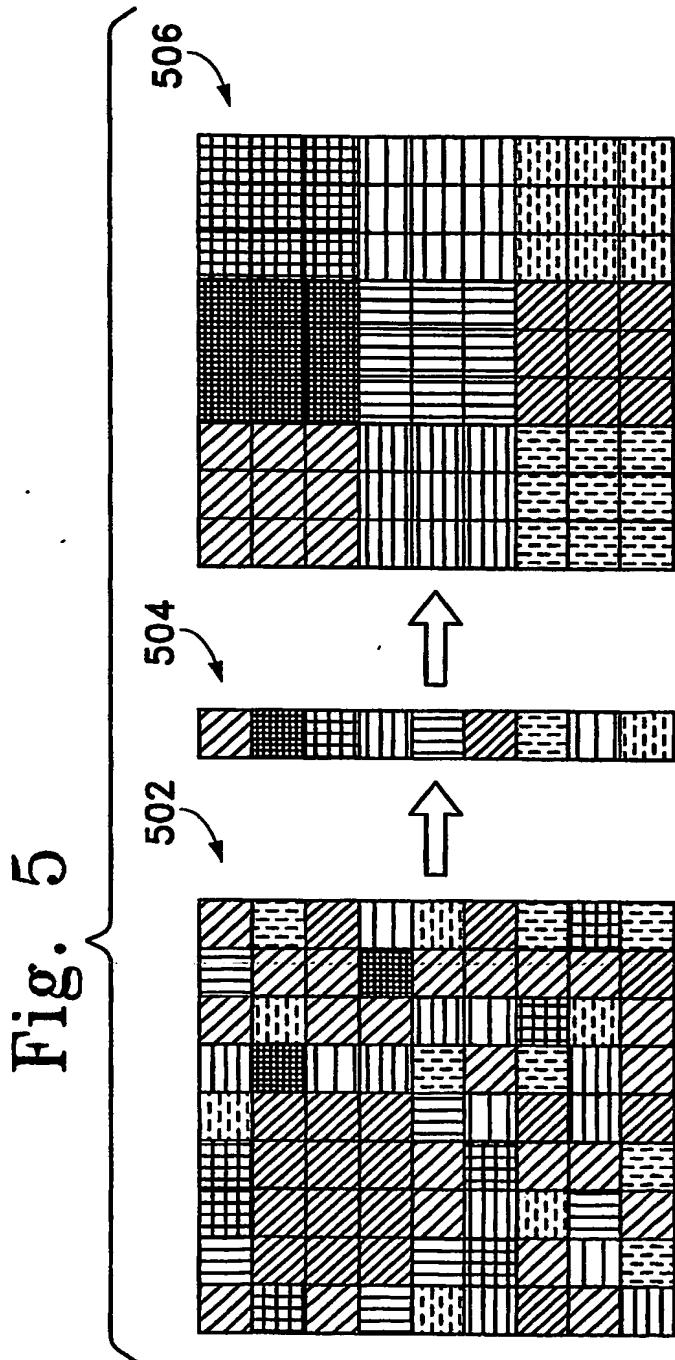
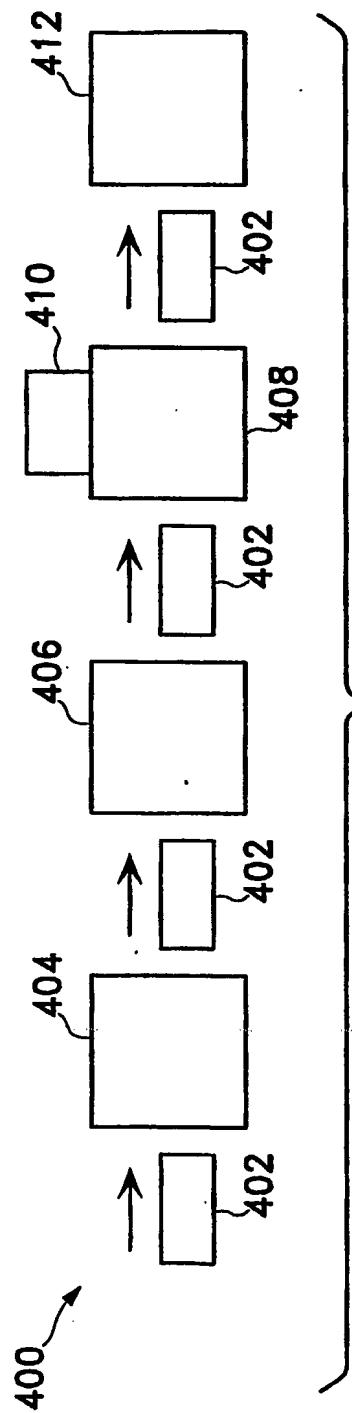


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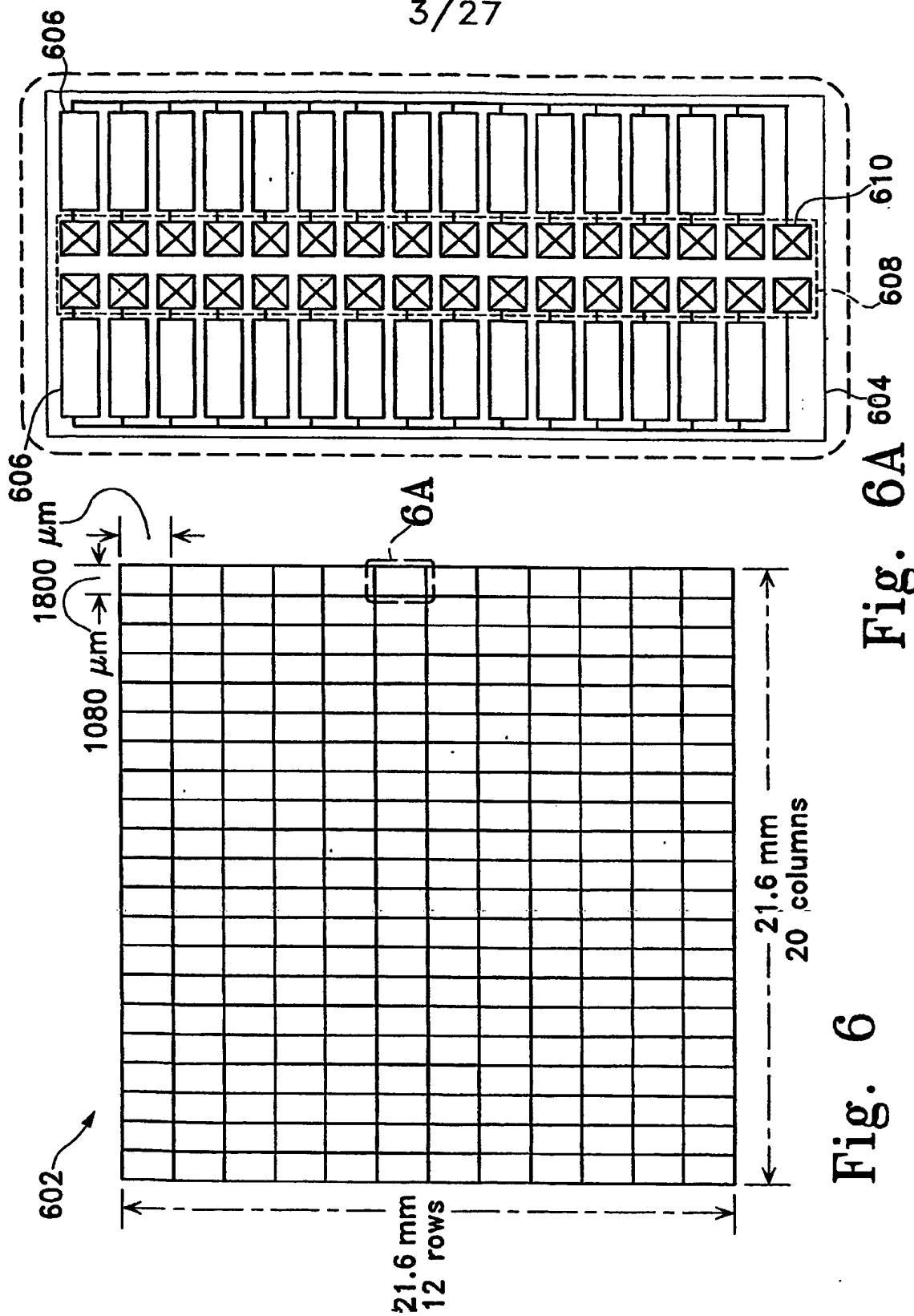
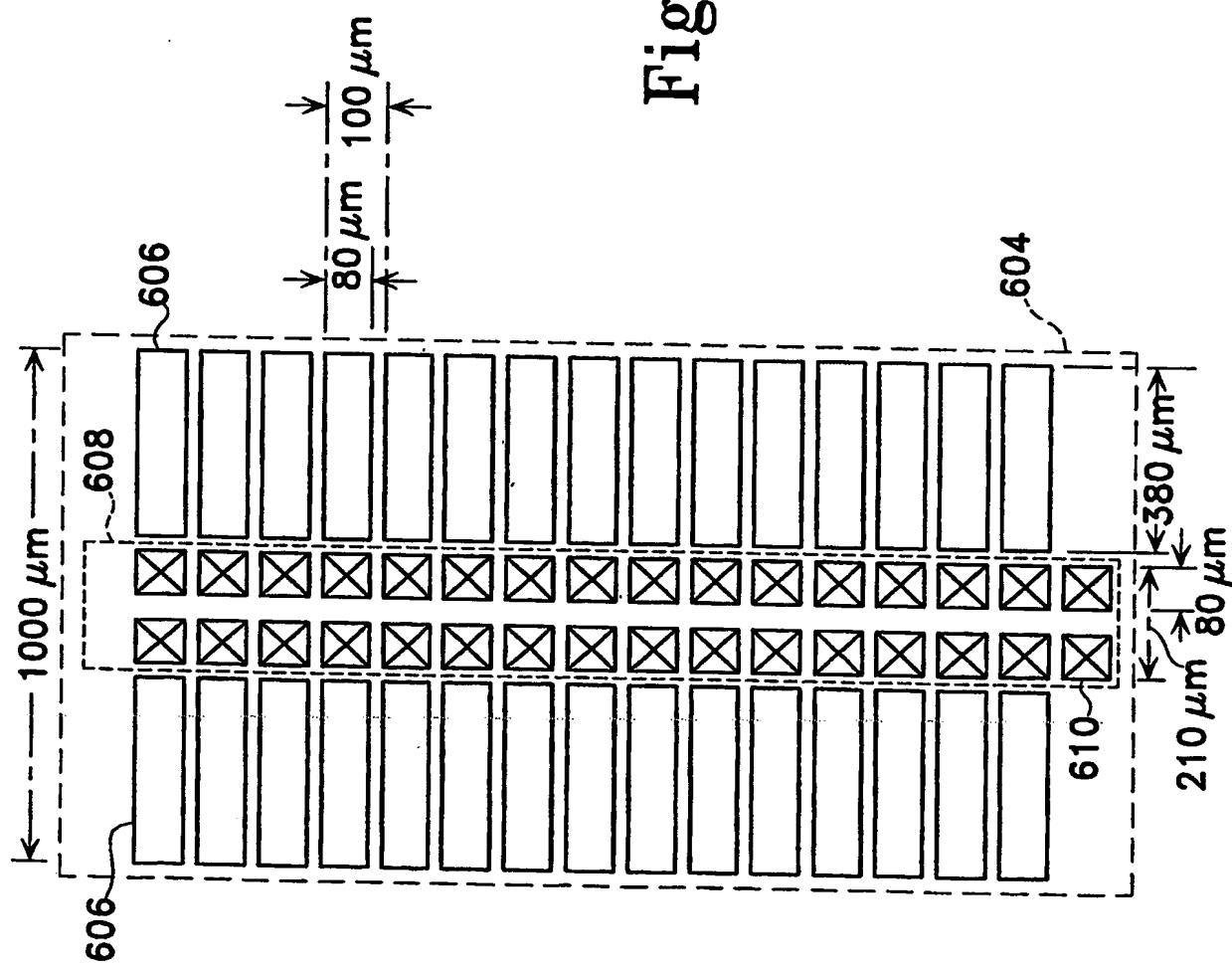


Fig. 6

Fig. 6A

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Fig. 7



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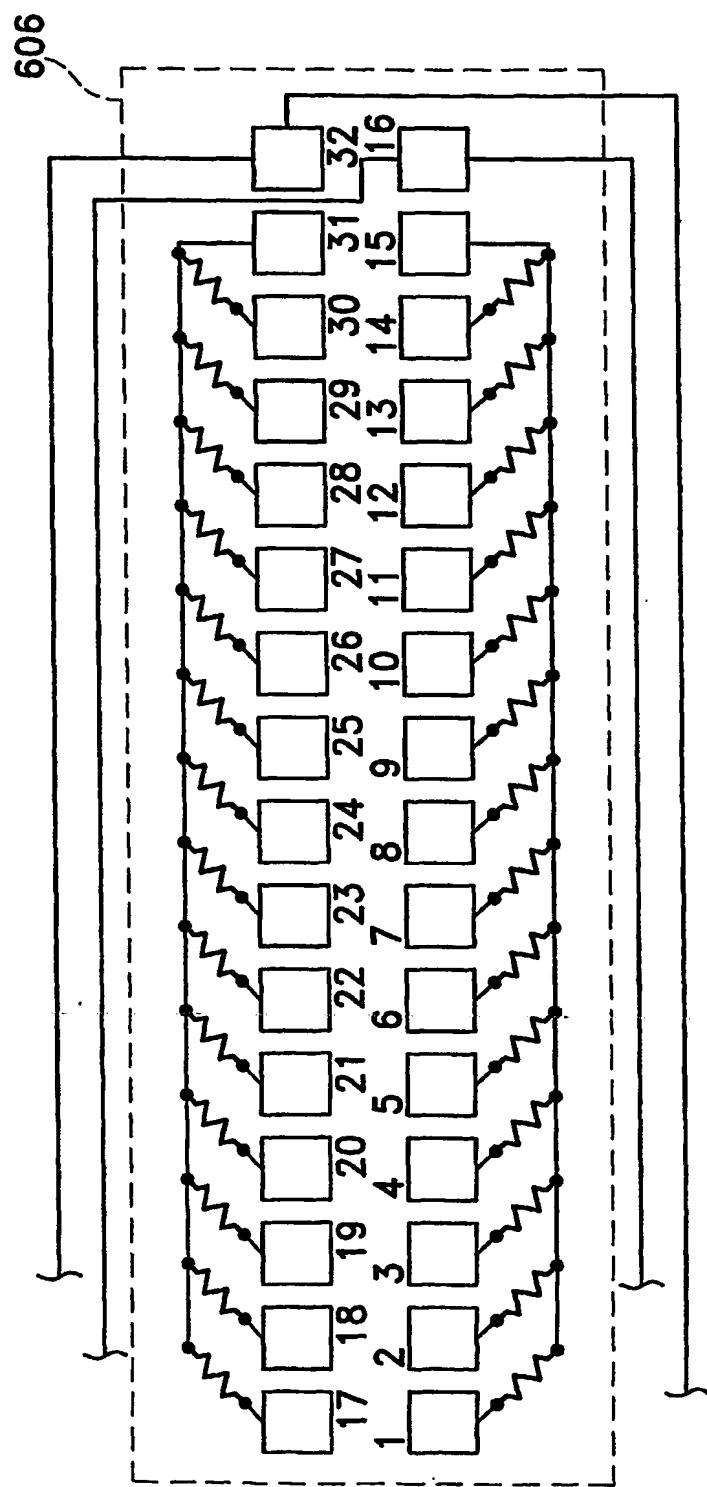
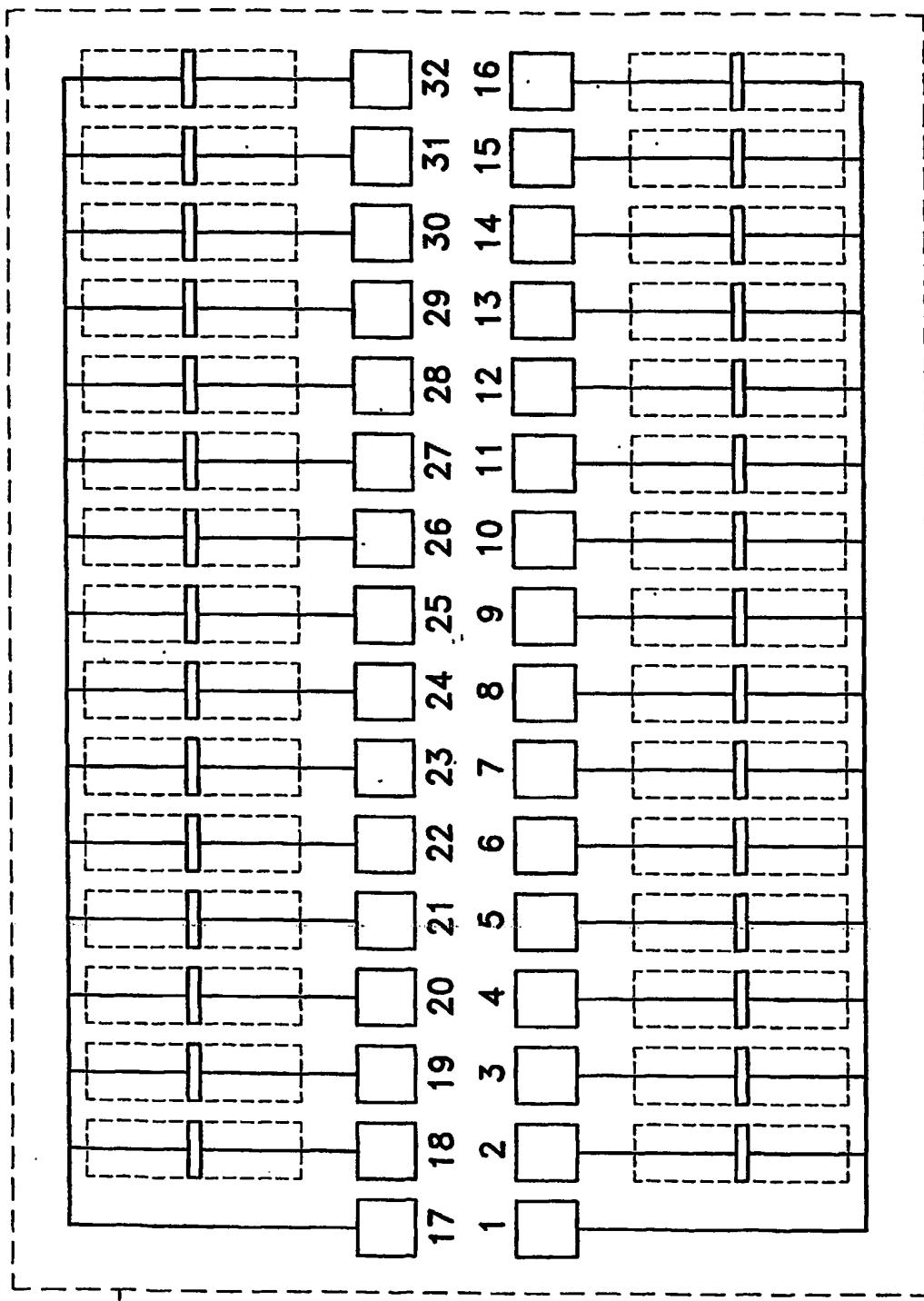


Fig. 8

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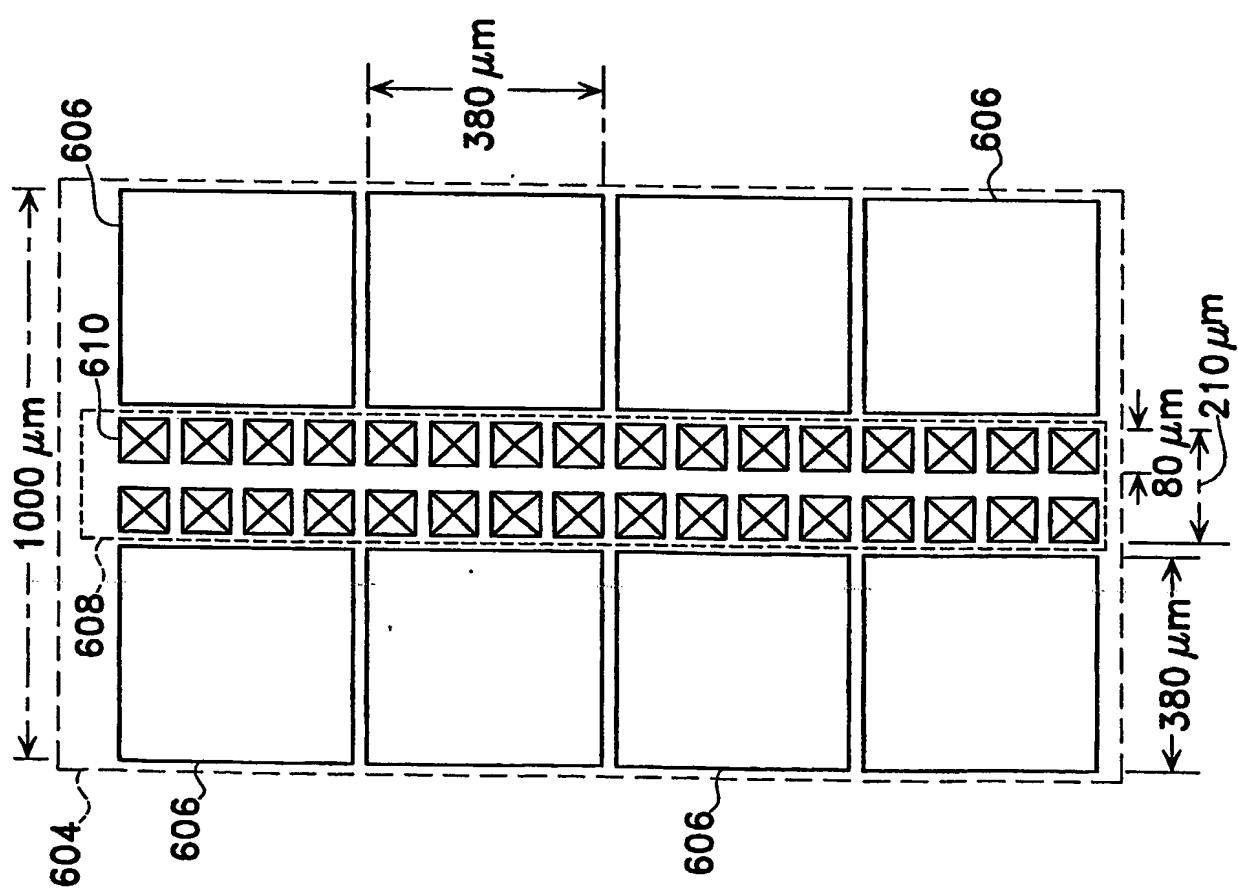


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Fig.

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Fig. 10



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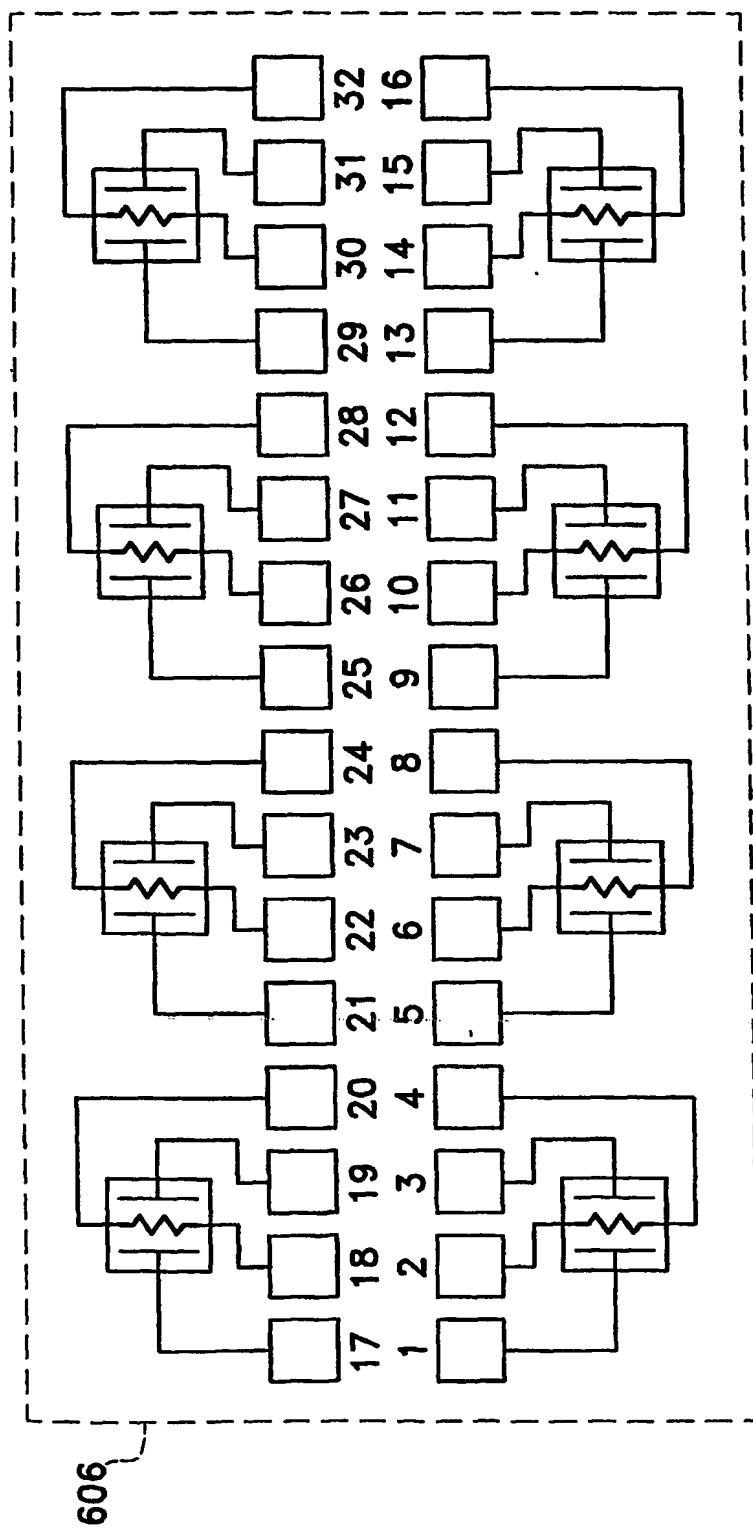


Fig. 11

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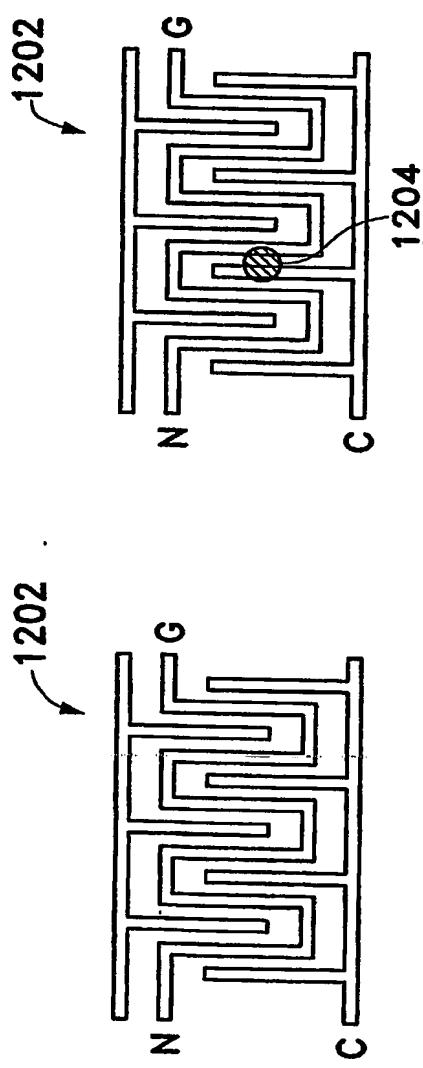


Fig. 12A

Fig. 12B

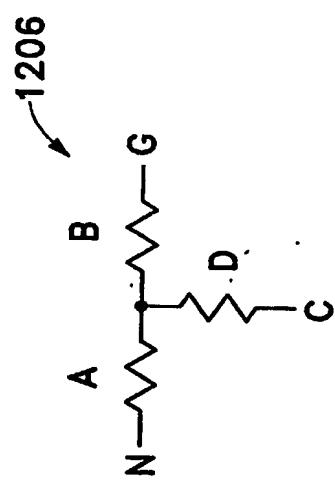
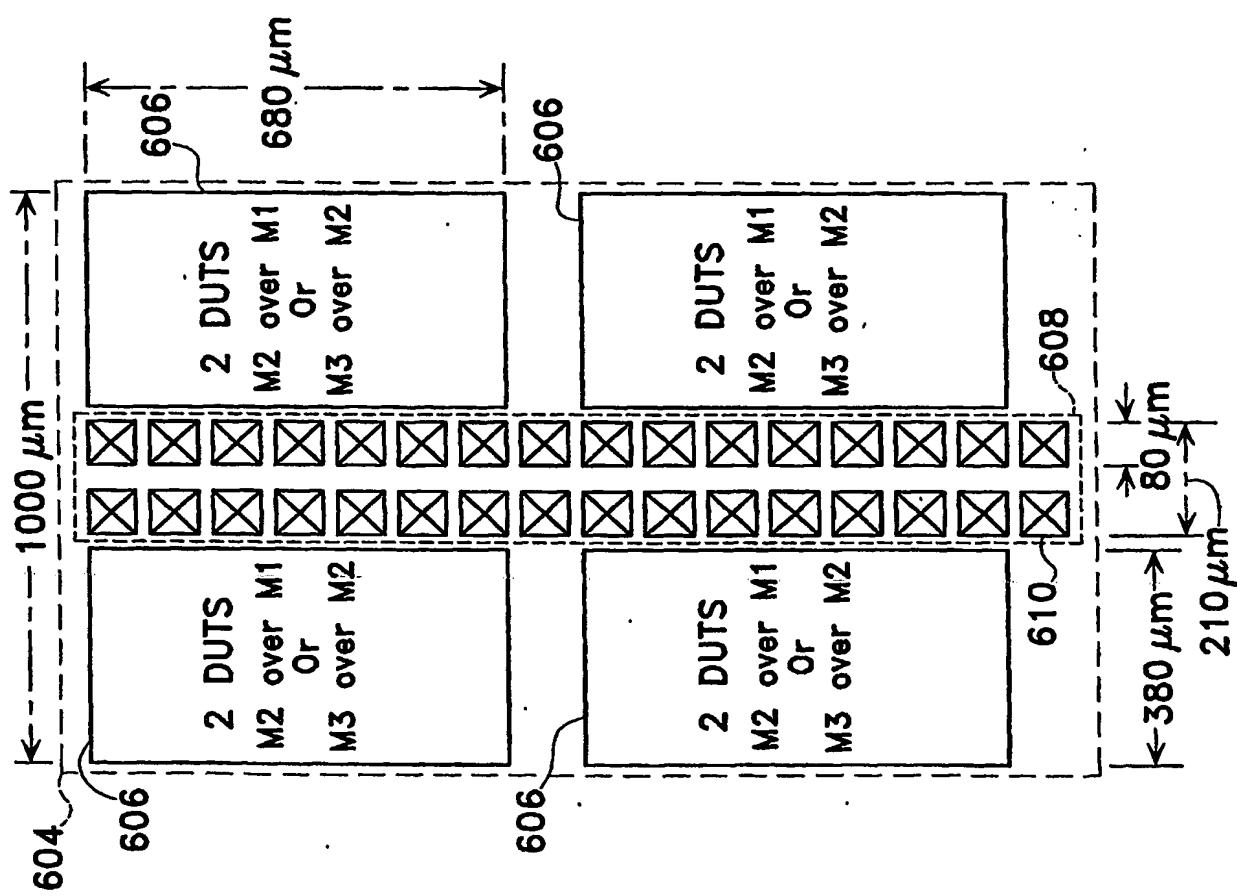


Fig. 12C

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Fig. 13



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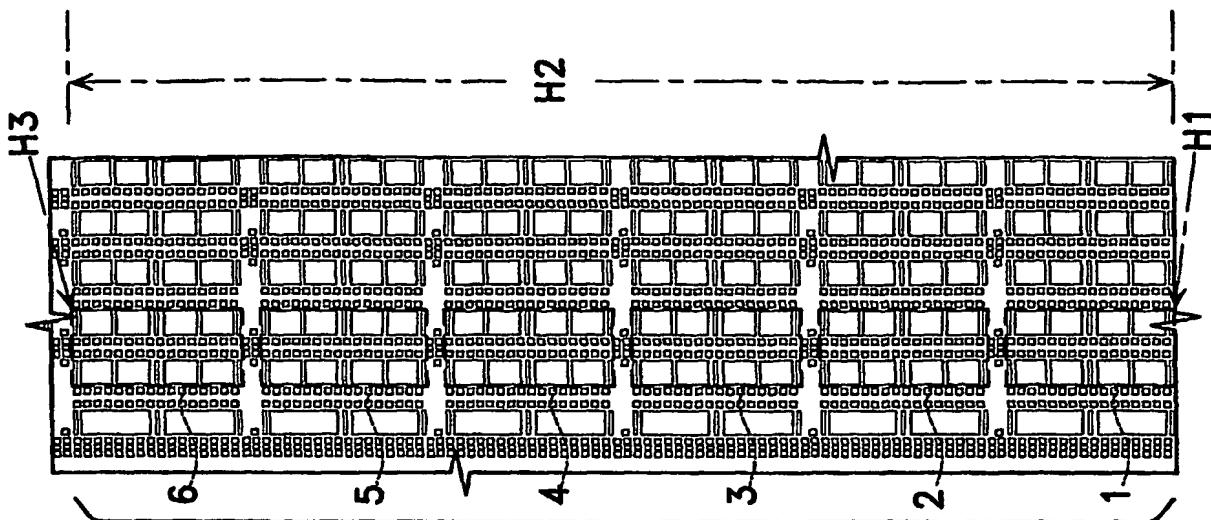


Fig. 15

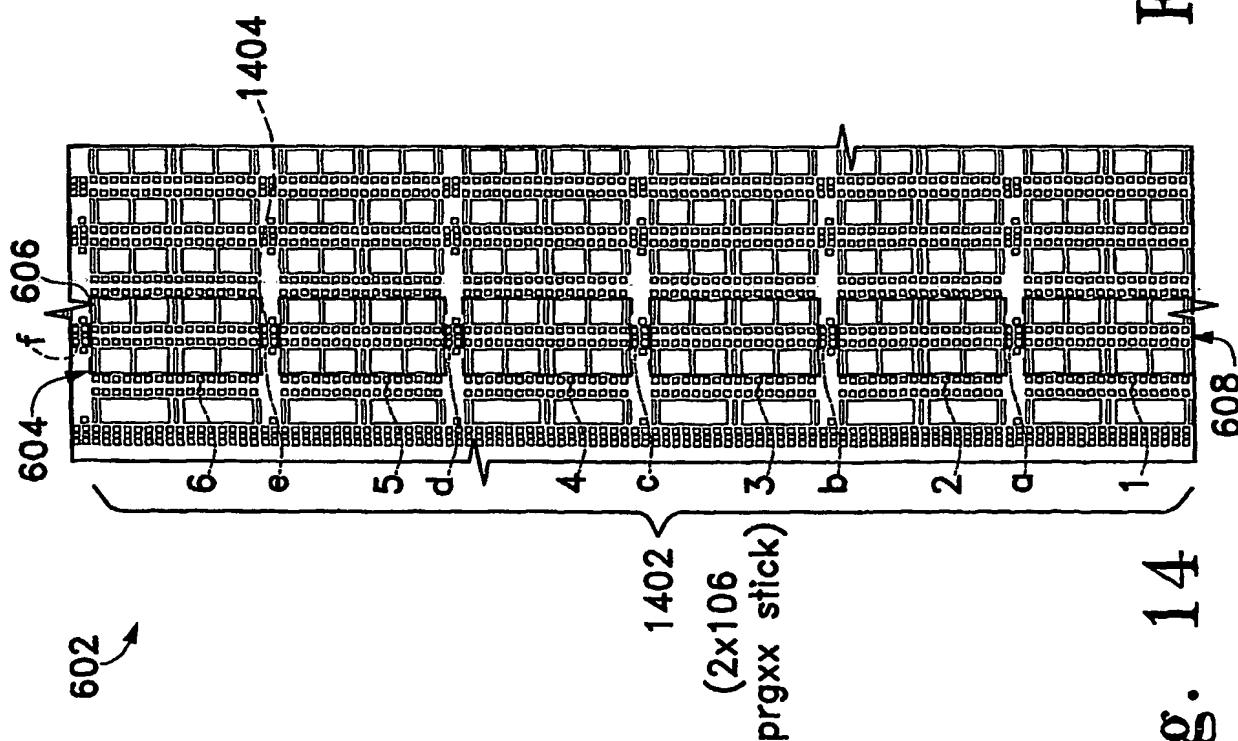


Fig. 14

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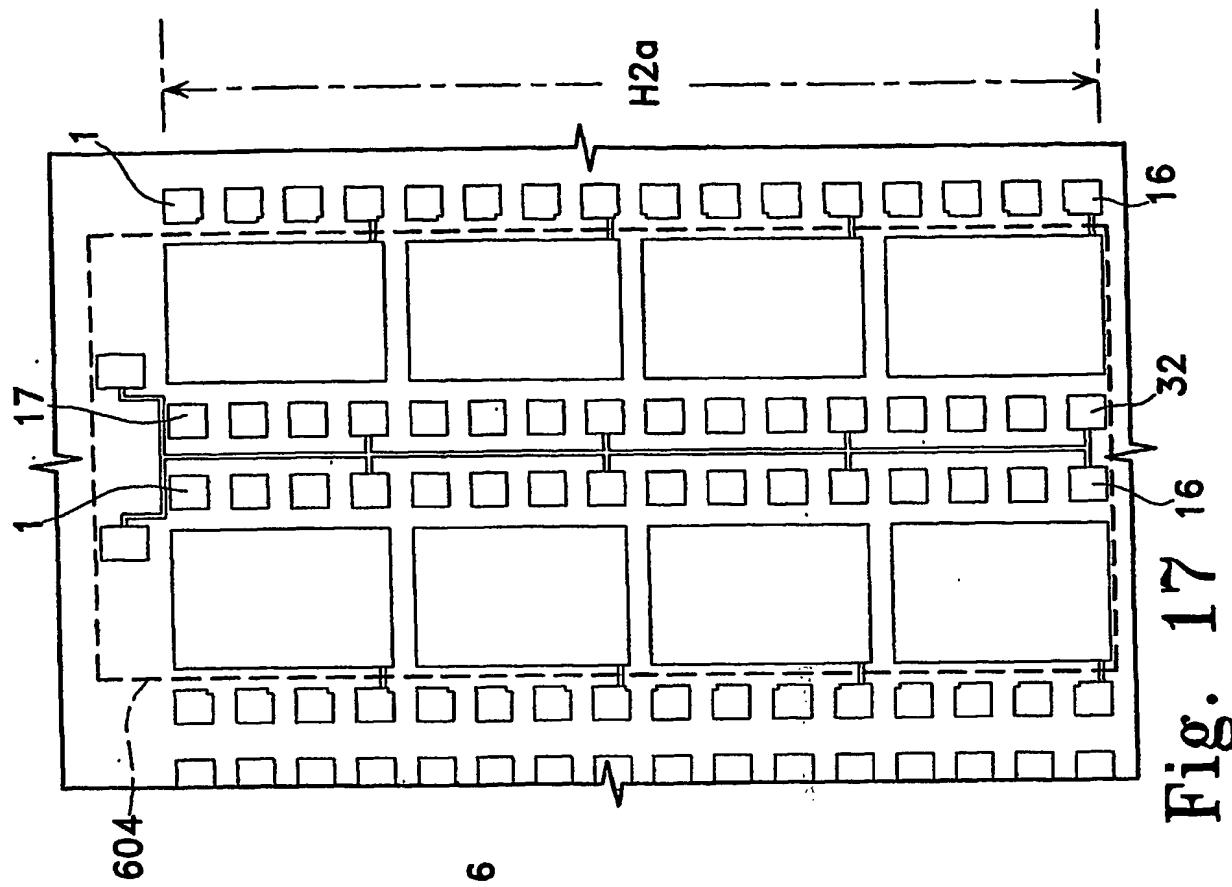


Fig. 17

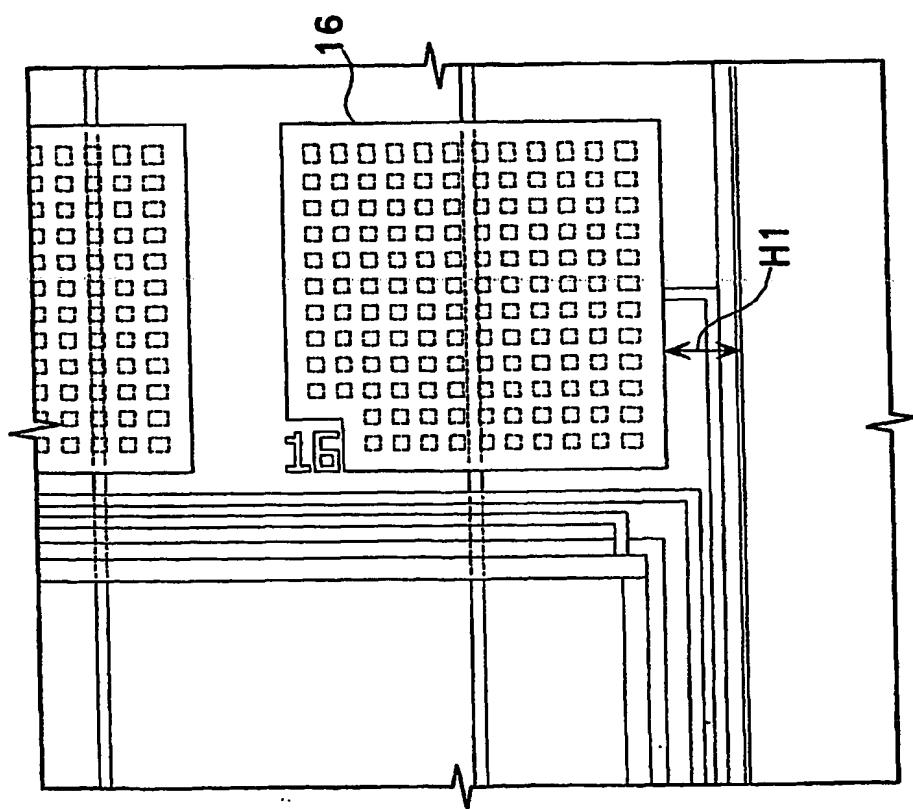
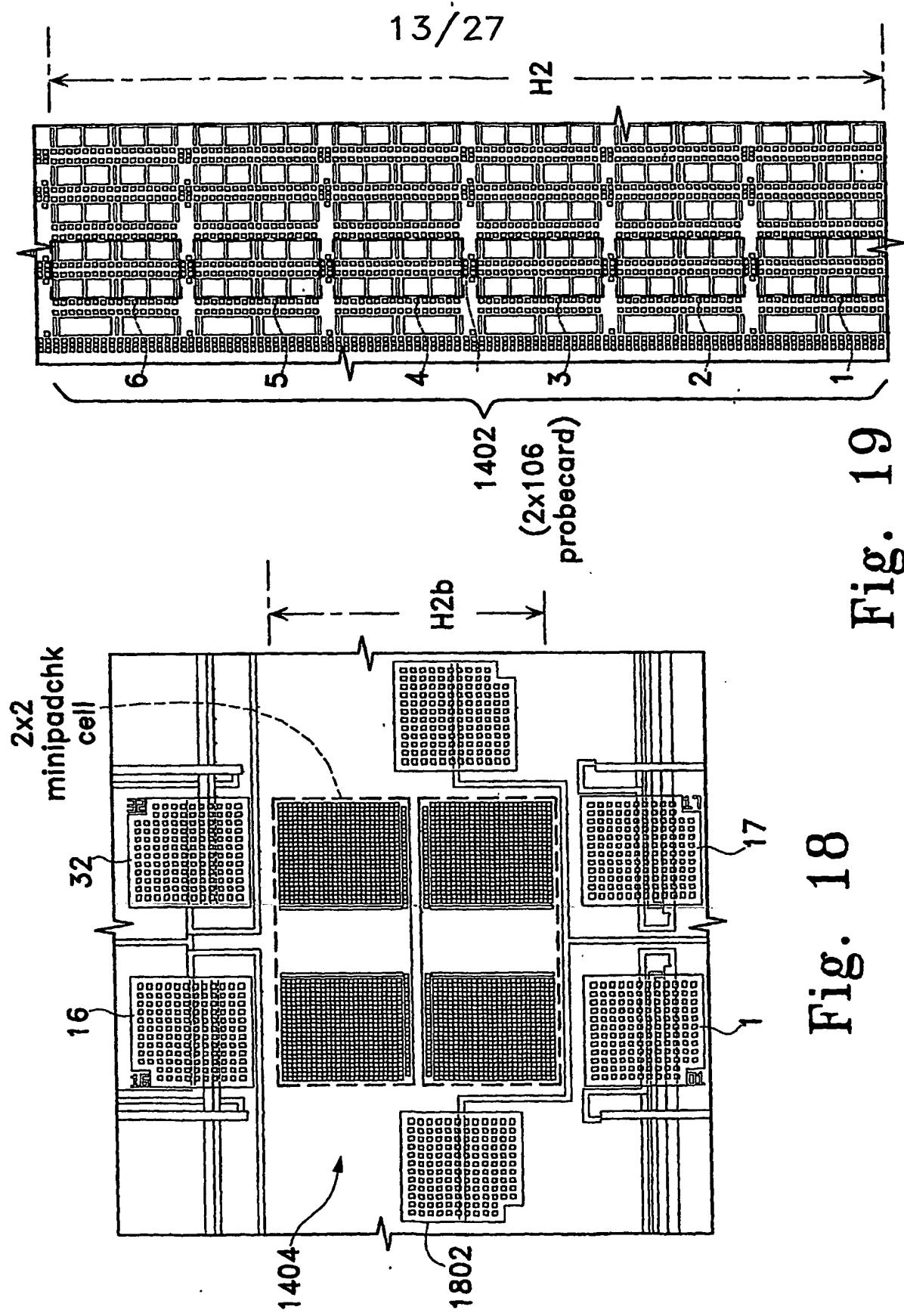


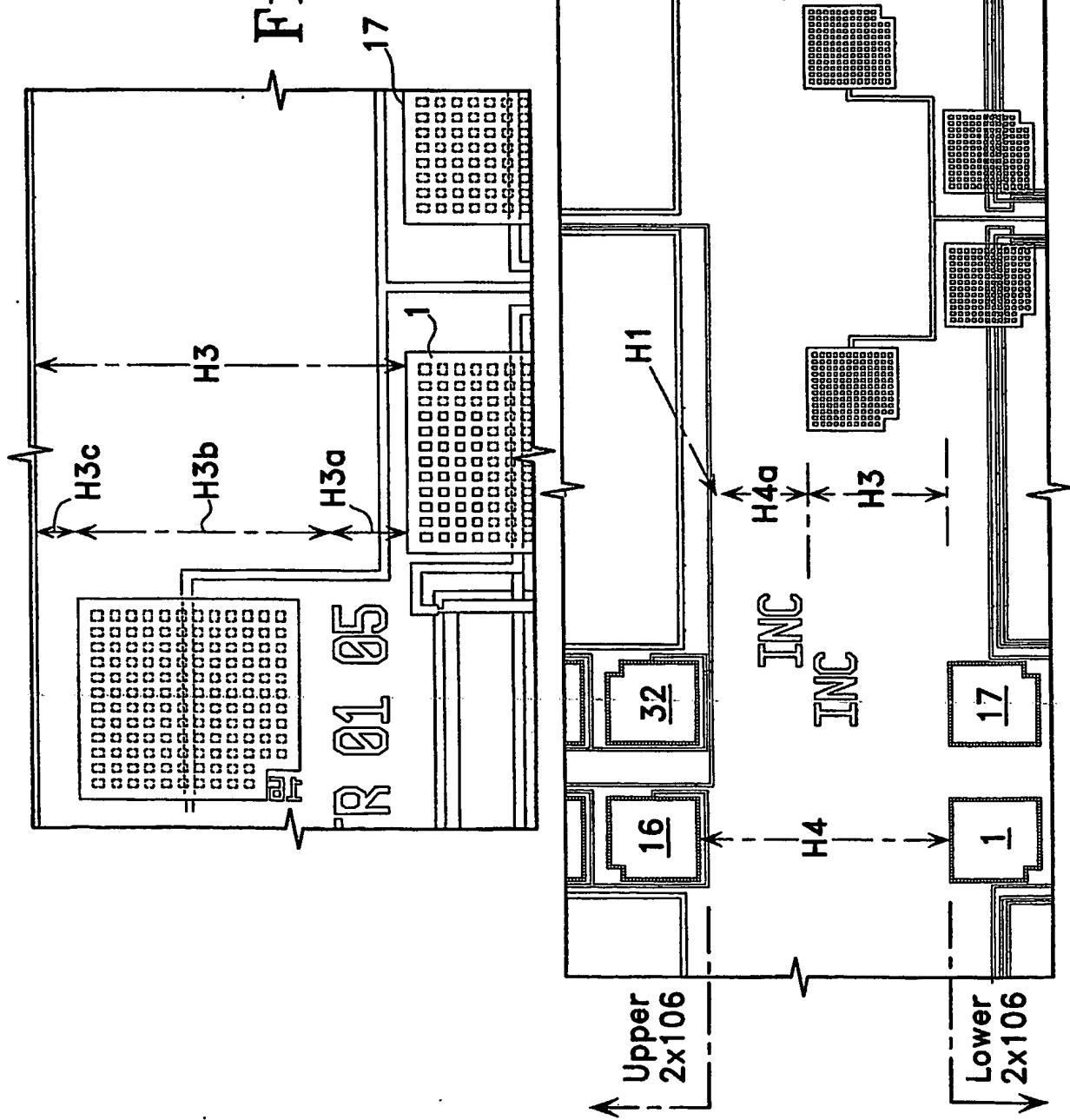
Fig. 16



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Fig. 21

Fig. 20



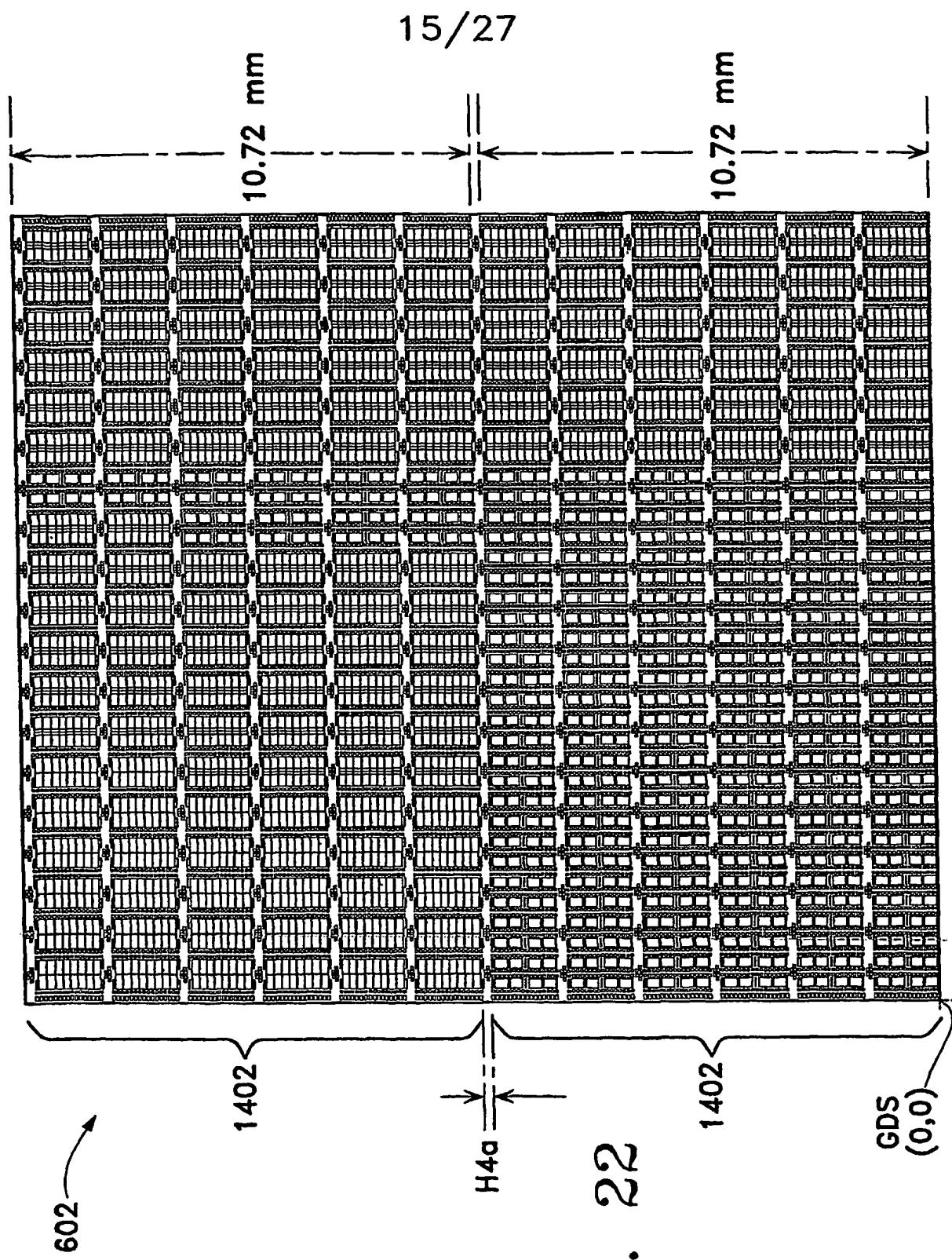


Fig. 22

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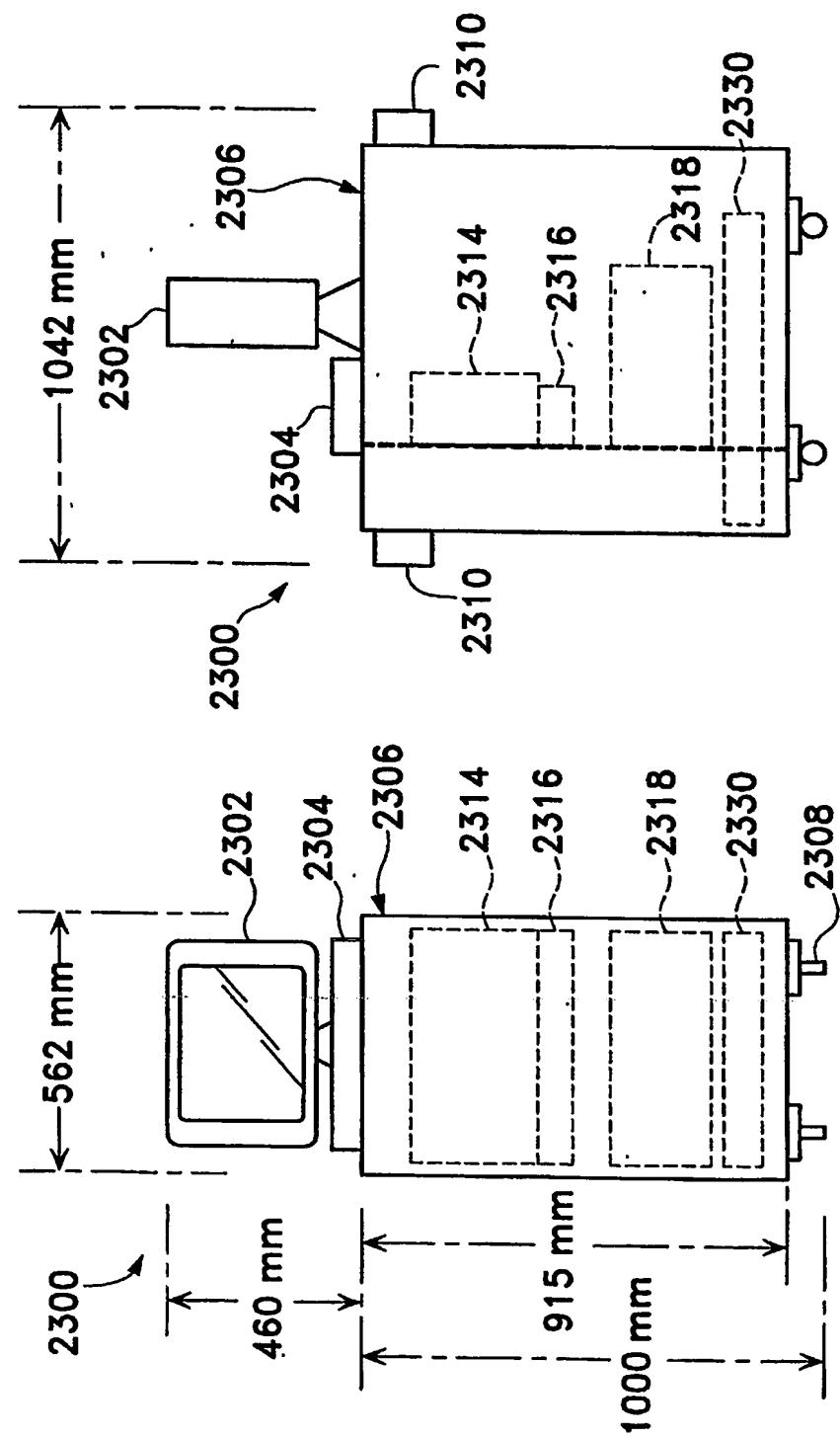


Fig. 23

Fig. 24

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Fig. 25

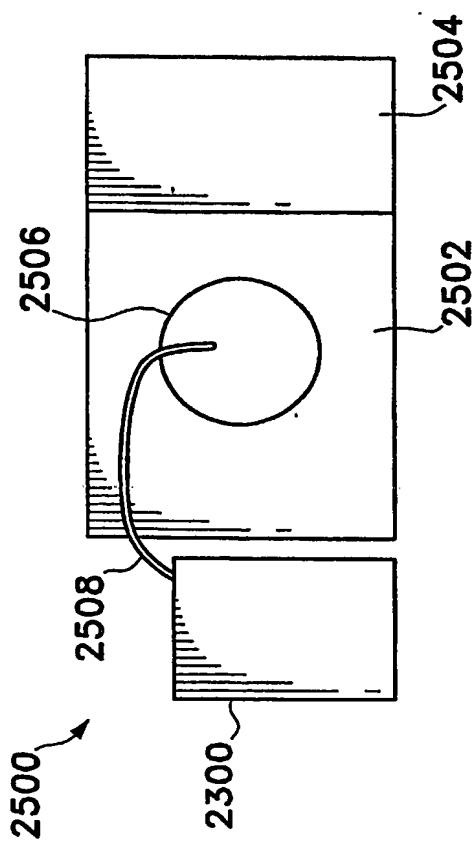
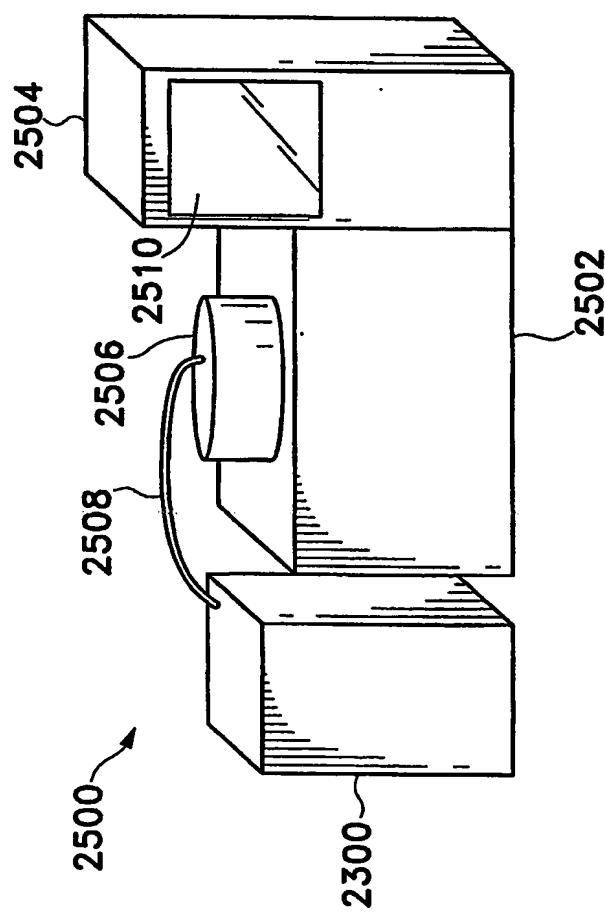


Fig. 26



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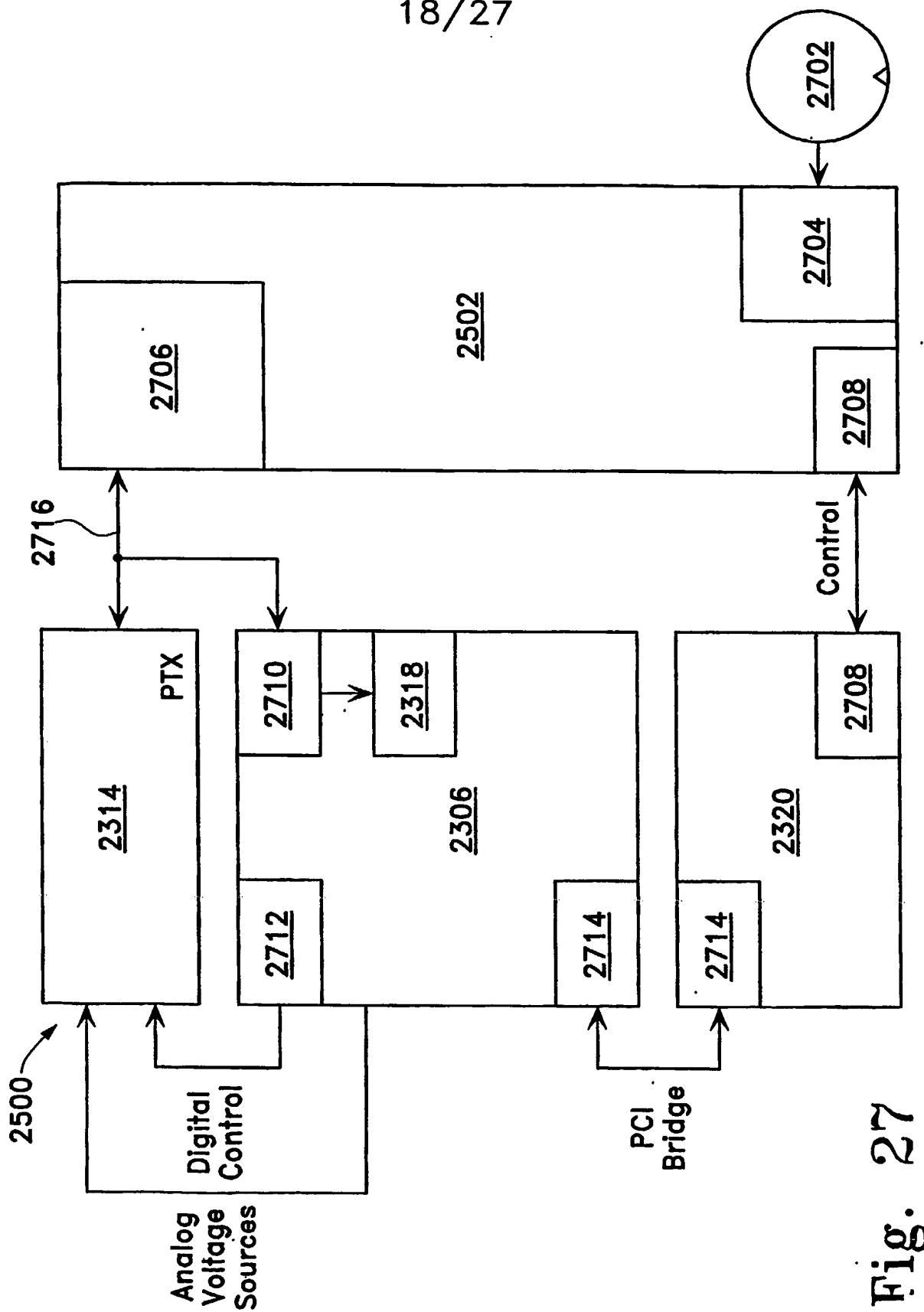
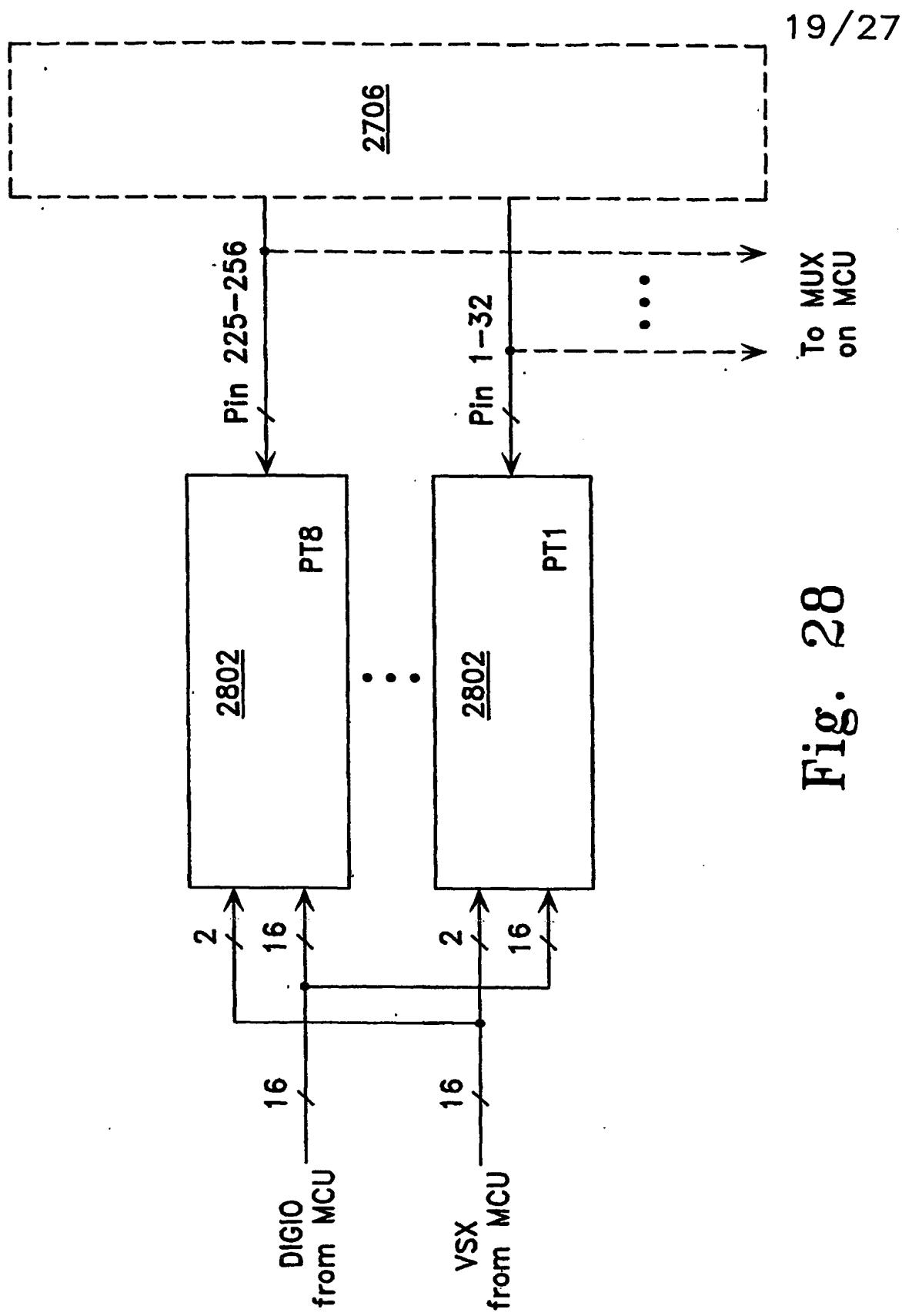


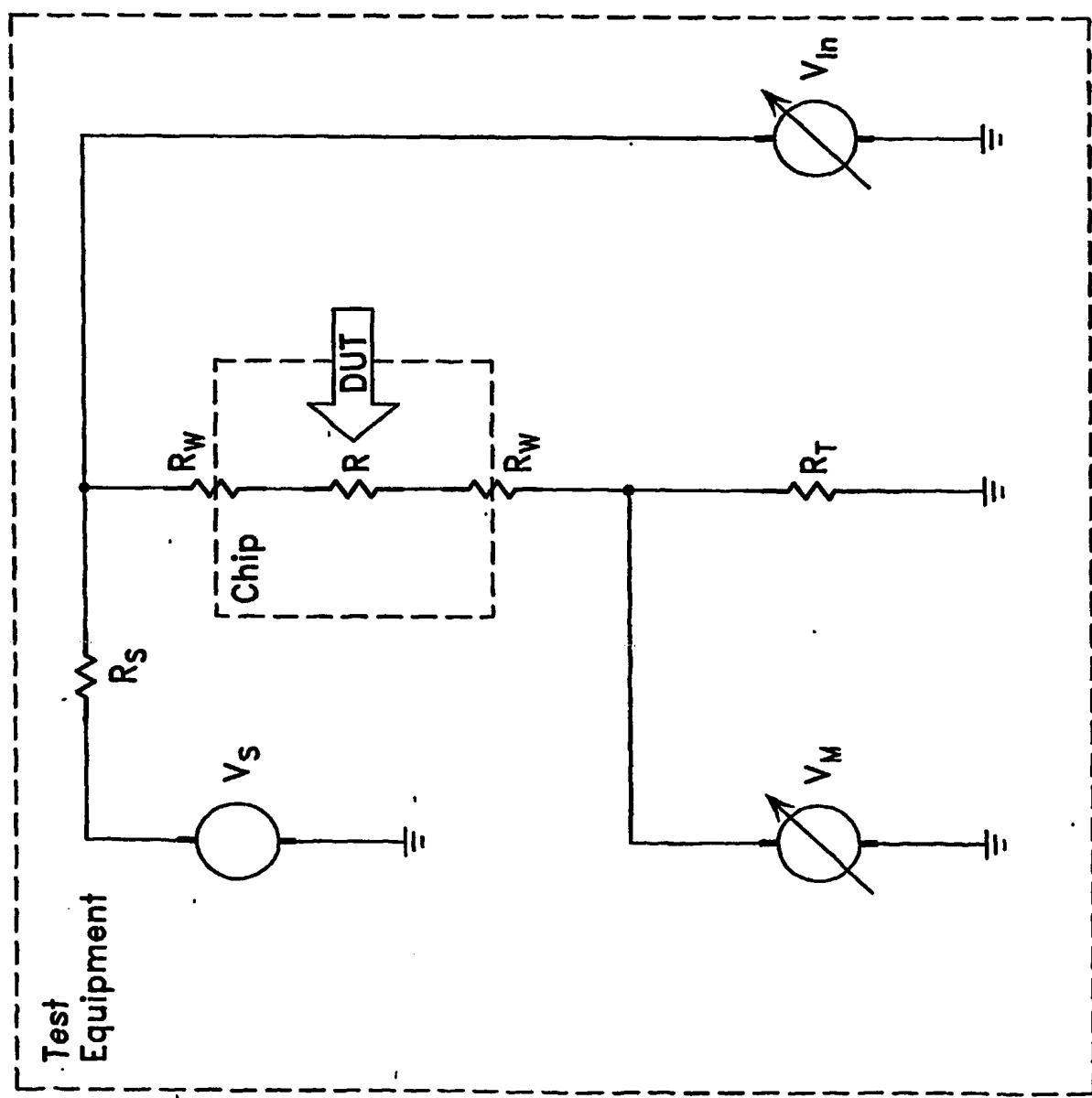
Fig. 27



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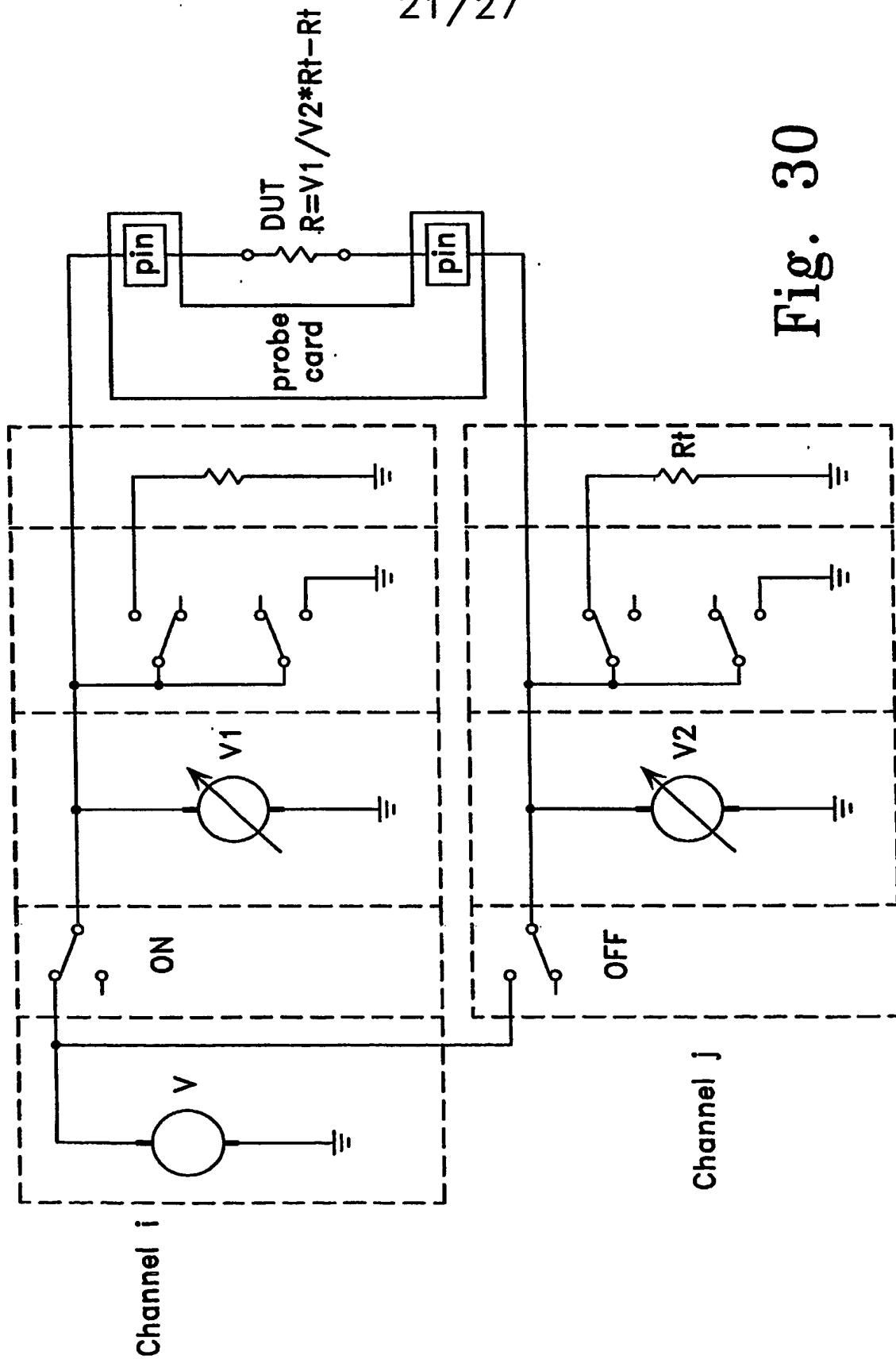
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Fig. 29



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Fig. 30



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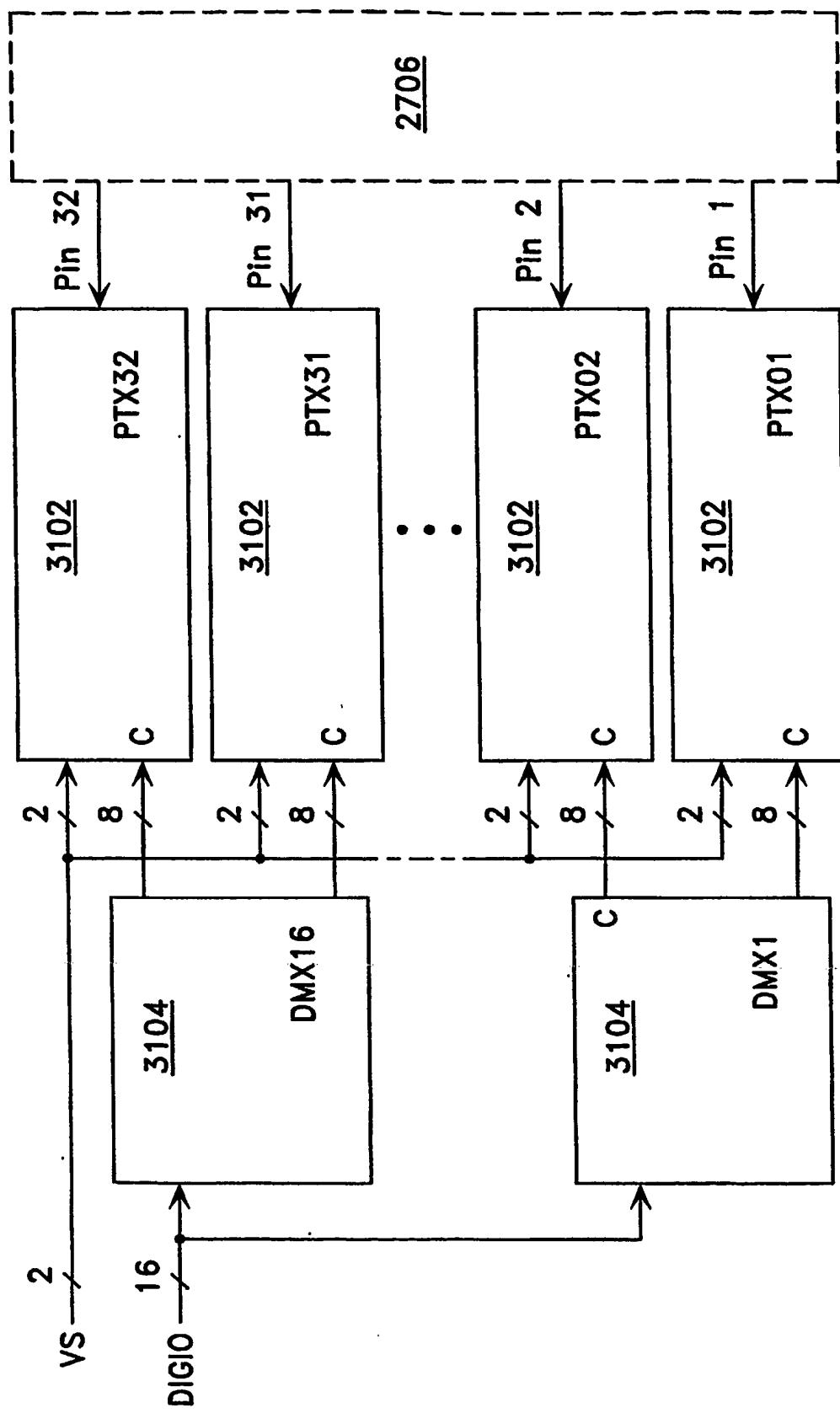


Fig. 31

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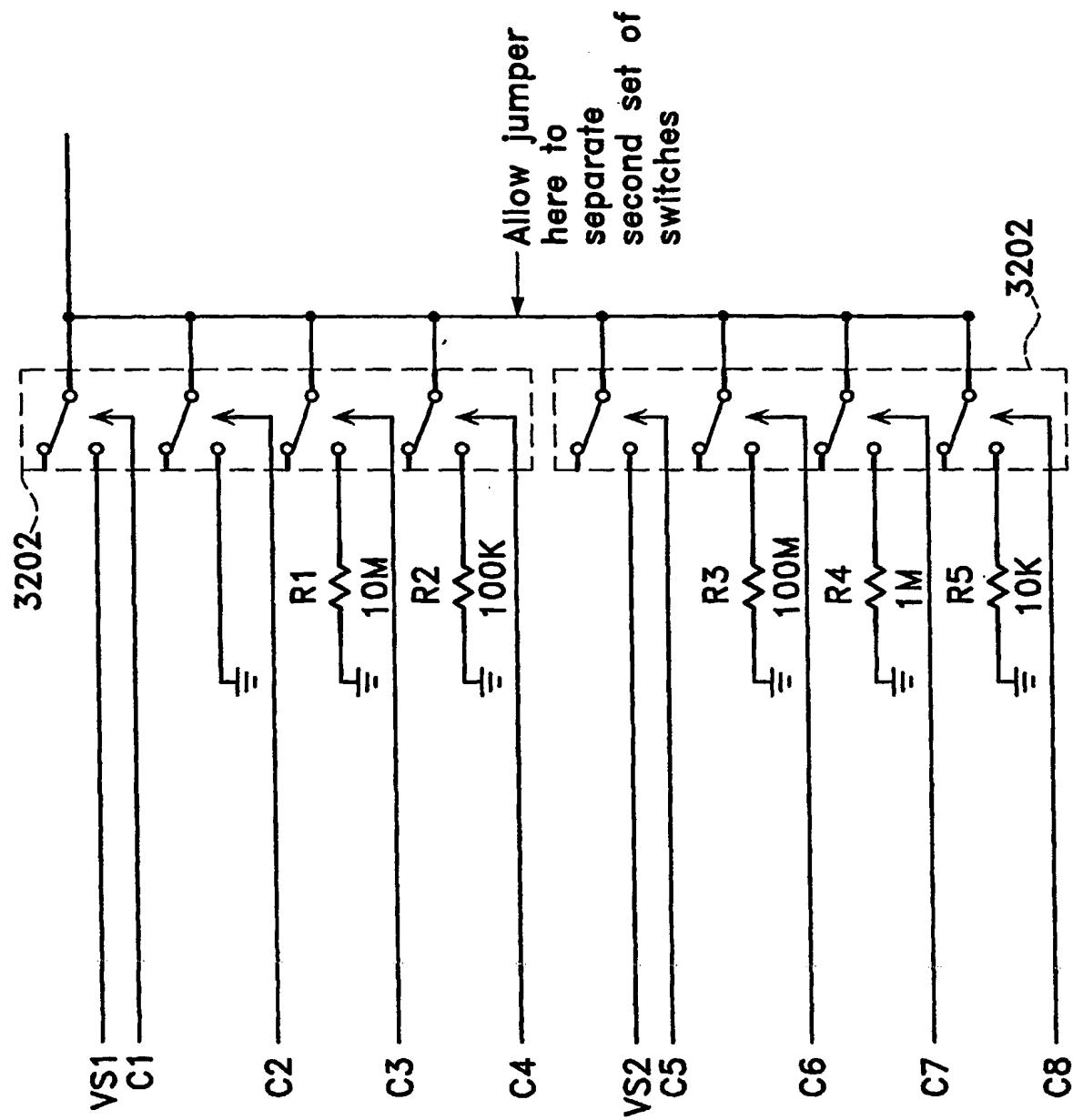


Fig. 32

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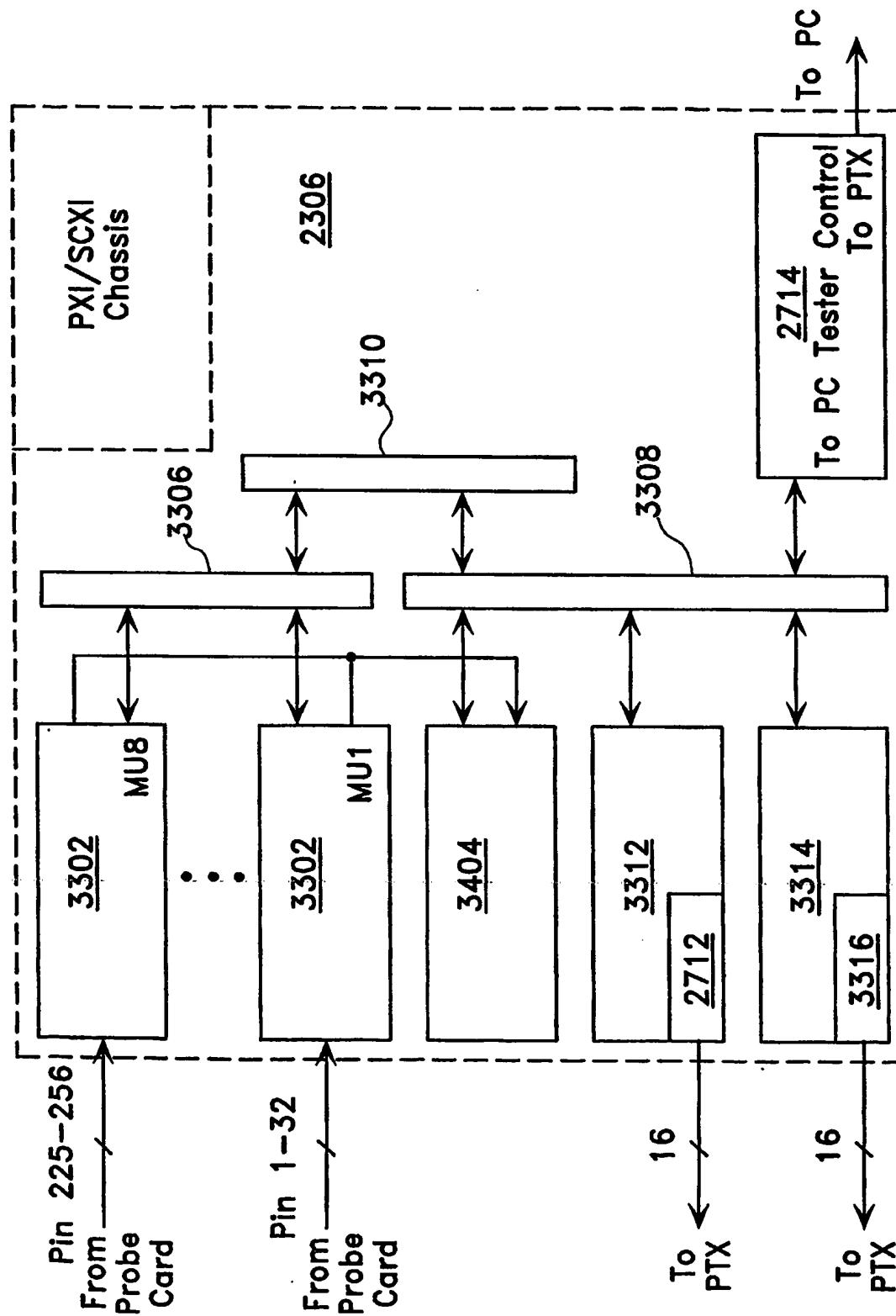
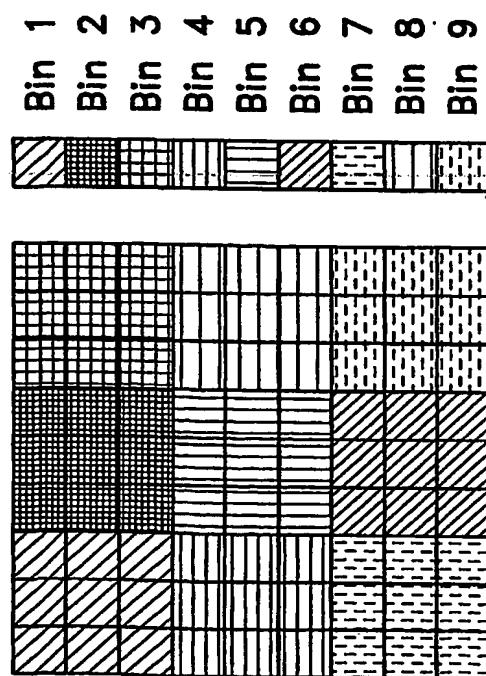


Fig. 33

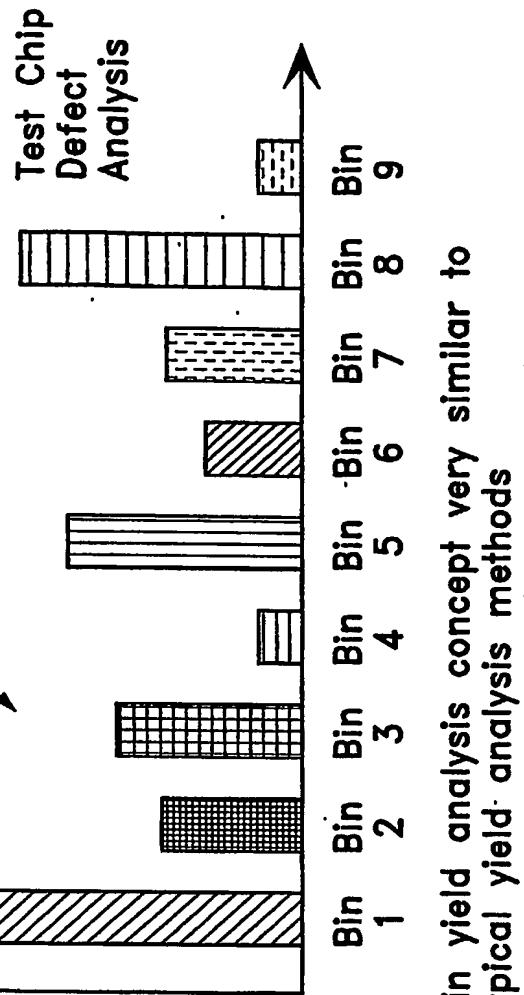
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Fig. 34



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→ Bin yield analysis concept very similar to typical yield analysis methods

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Fig. 35

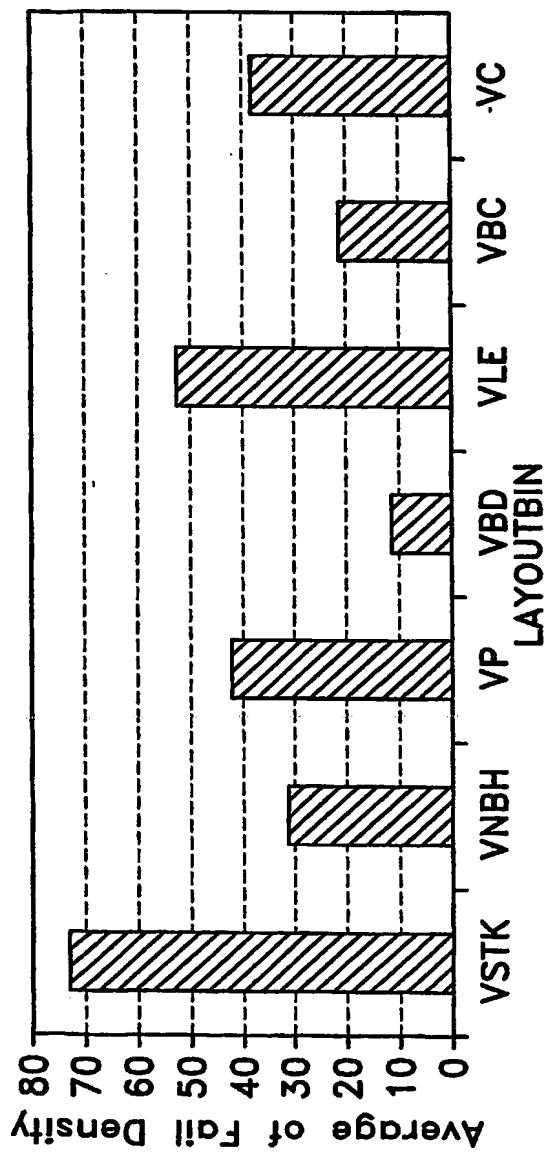
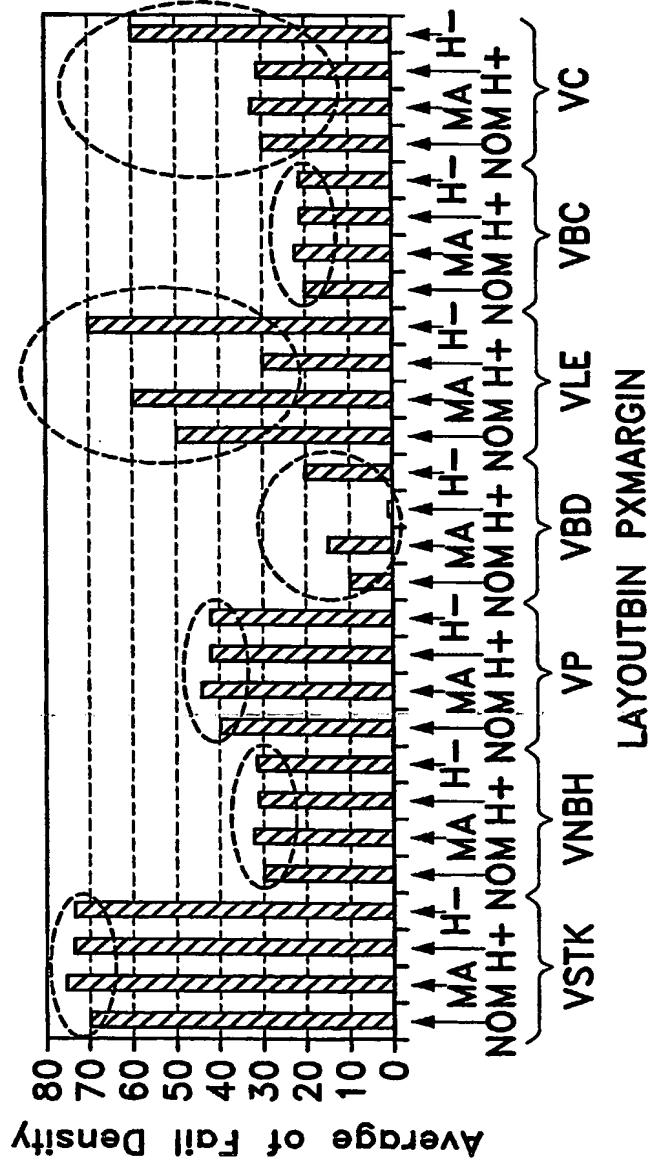


Fig. 36



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Fig. 37

